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ASA-1236

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Y. KOMIYA, et al.

Serial No.: 10/533,127

Filed: April 29, 2005

For: DEFECT ANALYSIS APPARATUS, SYSTEM AND METHOD
FOR SEMICONDUCTOR INTEGRATED CIRCUIT

**INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR §1.97 & 1.98**

MS Amendment

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

February 23, 2007

Sir:

In the matter of the above-identified application, Applicants are submitting herewith a copy of a communication from a foreign patent office in a counterpart foreign application and copies of the documents listed in the attached form equivalent to Form PTO-1449 for the Examiner's consideration.

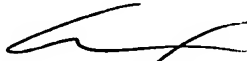
This information disclosure statement is being submitted before the mailing date of a first office action on the merits.

To the extent the documents listed on the attached form equivalent to Form PTO-1449 are not in the English language, the requirement of 37 CFR §1.98(a)(3) for a concise explanation of the relevance is satisfied by an English language version or translation of the foreign patent office report citing the documents.

It is respectfully requested that this information disclosure statement be considered by the Examiner.

Please charge any shortage in the fees due in connection with the filing of this paper, including extension of time fees, to the deposit account of MATTINGLY, STANGER, MALUR & BRUNDIDGE, P.C., Deposit Account No. 50-1417 (ASA-1236) please credit any excess fees to such deposit account.

Respectfully submitted,



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FORM PTO-1449 U.S. Department of
Commerce Patent and Trademark Office

ATTY. DOCKET NO.

SERIAL NO.

ASA-1236

10/533,127

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use several sheets if necessary)

APPLICANT

Y. KOMIYA, et al

FILING DATE

April 29, 2005

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER								DATE	COUNTRY	CLASS	SUBCLASS	ABSTRACT	
													YES	NO
	0	6	2	8	1	7	0	0	10/94	Japan			XX	
	0	9	1	5	2	4	7	2	6/97	Japan			XX	
	1	1	0	4	4	7	2	4	2/99	Japan			XX	
	2 0 0 1	1	6	6	0	1	2		6/01	Japan			XX	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation is considered, draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

(Form PTO-1449 [6-4])